

NISTTech

MICROSCOPE PROBE AND METHOD FOR USE OF SAME

Docket No. 13-017

Advantages

- **Superior**
greater sensitivity and stability, higher measurement bandwidth, and the ability to excite the probe and tune the transfer function for specific applications

Abstract

The current invention is a novel probe for AFM (atomic force microscopy). AFM's are limited in sensitivity, speed, stability, size, and cost by the currently used cantilever probes and the associated optical motion measurement techniques. The current invention enables superior sensitivity, measurement bandwidth, stability, and the ability to "excite" the probe and tune the transfer function for specific applications by integrating a microscale optical interferometer for motion measurement directly on the chip.

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References

- US Patent No. 8,997,258

Status of Availability

This invention is available for licensing exclusively or non-exclusively in any field of use.

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